

AMENDMENTS TO THE CLAIMS:

The following listing of claims replaces all prior listings, and all prior versions, of claims in the application.

LISTING OF CLAIMS:

[1] (Currently amended) A manufacturing method of a semiconductor device comprising the steps of:

(a) preparing a first raw material gas which contains a silane-based compound gas containing carbon atoms with the first concentration of 0.3% or more in a first hydrogen gas;

(b) producing a first diluted raw material gas containing the silane-based compound gas with the second concentration lower than the first concentration by diluting the first raw material gas with a second hydrogen gas;

(c) supplying, after the step (b), at least a first portion of the first diluted raw material gas into the inside of a reaction chamber in which a wafer to be processed is accommodated; and

(d) forming a SiGe:C epitaxial layer or a SiGe:C-based epitaxial layer on a first main surface of the wafer to be processed using the first portion of the supplied ~~first~~ first diluted raw material gas,

wherein a remaining second portion of the first diluted raw material gas is not supplied to the inside of the reaction chamber.

[2] (Cancelled).

[3] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the first hydrogen gas and the second hydrogen gas have the substantially same concentration composition.

[4] (Original) A manufacturing method of a semiconductor device according to claim 3, wherein the purity of the second hydrogen gas is 99.99% or more.

[5] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the reaction chamber is an epitaxial layer forming reaction chamber of a single wafer epitaxial device.

[6] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the reaction chamber is an epitaxial layer forming reaction chamber of a batch-type epitaxial device.

[7] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the epitaxial layer constitutes a portion of a base region of a HBT.

[8] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the epitaxial layer is a channel region of a strain SiGe-based MISFET.

[9] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of dilution of the first diluted raw material gas is set to a value which falls within a range from 2 to 100.

[10] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of dilution of the first diluted raw material gas is set to a value which falls within a range from 3 to 50.

[11] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of dilution of the first diluted raw material gas is set to a value which falls within a range from 4 to 20.

[12] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of dilution of the first diluted raw material gas is set to a value which falls within a range from 6 to 15.

[13] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of introduction of the first diluted raw material gas is set to a value which falls within a range from 2 to 100.

[14] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of introduction of the first diluted raw material gas is set to a value which falls within a range from 3 to 50.

[15] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of introduction of the first diluted raw material gas is set to a value which falls within a range from 4 to 20.

[16] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the degree of introduction of the first diluted raw material gas is set to a value which falls within a range from 6 to 15.

[17] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the first concentration is equal to or more than 0.6%.

[18] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the first concentration is equal to or more than 1%.

[19] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the first concentration is equal to or more than 2%.

[20] (Original) A manufacturing method of a semiconductor device according to claim 1, wherein the first concentration is equal to or more than 5%.